

PCN Number:	20150714000		PCN Date:	07/17/2015	
Title:	UCC28600 Die Revision Change				
Customer Contact:	PCN Manager		Dept:	Quality Services	
Proposed 1st Ship Date:	10/17/2015	Estimated Sample Availability:	Date provided at sample request.		
Change Type:					
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials
<input checked="" type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process
<input type="checkbox"/>		<input type="checkbox"/>	Part number change		
PCN Details					
Description of Change:					
<p>This notification is to inform of a die revision change to select devices. The design change does not affect the device's guaranteed datasheet specifications or electrical performance. The Design changes were made to:</p> <ol style="list-style-type: none"> 1. Improve high temperature operation. 2. Improve noise immunity on VDD. <p>Affected devices are listed in "Product Affected" section.</p>					
Reason for Change:					
Improved product performance					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):					
None					
Changes to product identification resulting from this PCN:					
Die Rev designator will change as shown in the table and sample label below:					
Current	New				
Die Rev [2P]	Die Rev [2P]				
A	C				
Sample product shipping label to indicate die rev location (not actual product label)					
<p> TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 20: MSL 2 / 260C / 1 YEAR SEAL DT MSL 1 / 235C / UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L)T0:1750 </p> <p> (1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483SI2 (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CCO: USA (22L) AS0: MLA (23L) ACO: MYS </p>					
Product Affected:					
TPS92010D	UCC28600D	UCC28600DR	UCL64010D		
TPS92010DR	UCC28600DG4	UCC28600DRG4	UCL64010DR		

Qualification Report

UCC28600 PG3 Qual

Approved June 29, 2015

Product Attributes

Attributes	Qual Device: UCC28600	QBS Product Reference: TPS92010	QBS Product Reference: UCC28600	QBS Product Reference: UCC28600	QBS Process Reference: TPS40211DGQR	QBS Package Reference: TPS2042BD	QBS Package Reference: TPS2419DR
Assembly Site	FMX	MEX	FMX	FMX	ASESH	FMX	FMX
Package Family	SOIC	-	SOIC	SOIC	VSSOP	-	-
Wafer Fab Supplier	DFAB	DLN	DLN	DLN	DFAB	HIJI	MIHO
Wafer Process	LBC4	LBC4/200 BOAC	LBC4/200 BOAC	LBC4/200 BOAC	LBC4	LBC4X	LBC7

- QBS: Qual by Similarity

- Qual Devices qualified at LEVEL1-260CG: UCC28600, UCC28600, UCC28600

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: UCC28600	QBS Product Reference: TPS92010	QBS Product Reference: UCC28600	QBS Product Reference: UCC28600	QBS Process Reference: TPS40211DGQR	QBS Package Reference: TPS2042BD	QBS Package Reference: TPS2419DR
AC	Autoclave 121C	96 Hours	-	-	-	-	-	3/231/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	1/30/0	1/30/0	1/30/0	-	1/30/0	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-	3/231/0
HBM	ESD - HBM	2000 V	1/3/0	1/3/0	1/3/0	1/3/0	-	-	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	1/3/0	1/3/0	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	1/77/0	2/154/0	2/154/0	-	-	-
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	-	-	3/231/0	-	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	-	-	-	3/231/0	3/231/0
LI	Lead Pull to Destruction	Leads	-	-	-	-	-	3/66/0	-
LU	Latch-up	(per JESD78)	1/6/0	1/5/0	1/6/0	1/6/0	-	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	1/77/0	1/77/0	1/77/0	3/231/0	3/231/0	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -65C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com